

RF Exposure Report

Report No.: SA171226E06

FCC ID: HV4-PN579X

Test Model: PN579X

Received Date: Dec. 26, 2017

Test Date: Feb. 02, 2018

Issued Date: Feb. 27, 2018

Applicant: Wacom Co., Ltd.

Address: 2-510-1 Toyonodai Kozo-shi Saitama-Ken Japan 349-1148

Issued By: Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch
Hsin Chu Laboratory

Lab Address: E-2, No.1, Li Hsin 1st Road, Hsinchu Science Park, Hsinchu City 300,
Taiwan R.O.C.

This report is for your exclusive use. Any copying or replication of this report to or for any other person or entity, or use of our name or trademark, is permitted only with our prior written permission. This report sets forth our findings solely with respect to the test samples identified herein. The results set forth in this report are not indicative or representative of the quality or characteristics of the lot from which a test sample was taken or any similar or identical product unless specifically and expressly noted. Our report includes all of the tests requested by you and the results thereof based upon the information that you provided to us. You have 60 days from date of issuance of this report to notify us of any material error or omission caused by our negligence, provided, however, that such notice shall be in writing and shall specifically address the issue you wish to raise. A failure to raise such issue within the prescribed time shall constitute your unqualified acceptance of the completeness of this report, the tests conducted and the correctness of the report contents. Unless specific mention, the uncertainty of measurement has been explicitly taken into account to declare the compliance or non-compliance to the specification. The report must not be used by the client to claim product certification, approval, or endorsement by any government agencies.

Table of Contents

Release Control Record	3
1 Certificate of Conformity	4
2 Evaluation Result	5
3 SAR Test Exclusion Thresholds	6
4 Conclusion	6

Release Control Record

Issue No.	Description	Date Issued
SA171226E06	Original release.	Feb. 27, 2018

1 Certificate of Conformity

Product: Dell Premium Active Pen

Brand: Dell

Test Model: PN579X

Sample Status: ENGINEERING SAMPLE

Applicant: Wacom Co., Ltd.

Test Date: Feb. 02, 2018

Standards: FCC Part 2 (Section 2.1093)

KDB 447498 D01 General RF Exposure Guidance v06

IEEE C95.1-1992

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

Prepared by : Mary Ko , **Date:** Feb. 27, 2018
Mary Ko / Specialist

Approved by : May Chen , **Date:** Feb. 27, 2018
May Chen / Manager

2 Evaluation Result

Following FCC KDB 447498 D01 "General SAR test exclusion guidance"

The corresponding SAR Exclusion Threshold condition, listed below:

- 1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}]$$

$$\leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where}$$
 - $f(\text{GHz})$ is the RF channel transmit frequency in GHz.
 - Power and distance are rounded to the nearest mW and mm before calculation.
 - The result is rounded to one decimal place for comparison. The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.
- 2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following:
 - a) [Threshold at 50 mm in step 1) + (test separation distance - 50mm) $\cdot$ (f(MHz)/150)] mW, at 100MHz to 1500 MHz
 - b) [Threshold at 50 mm in step 1) + (test separation distance - 50 mm) $\cdot$ 10] mW at > 1500 MHz and ≤ 6 GHz
- 3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion.
 - a) The threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by $[1 + \log(100/f(\text{MHz}))]$ for test separation distances > 50 mm and < 200 mm.
 - b) The threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by $\frac{1}{2}$ for test separation distances ≤ 50 mm.
 - c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.

3 SAR Test Exclusion Thresholds

BT-LE Avg. Power Table

Channel	Frequency (MHz)	Peak Power		Avg. Power	
		(mW)	(dBm)	(mW)	(dBm)
0	2402	1.542	1.88	1.528	1.84
19	2440	1.6	2.04	1.578	1.98
39	2480	1.528	1.84	1.507	1.78

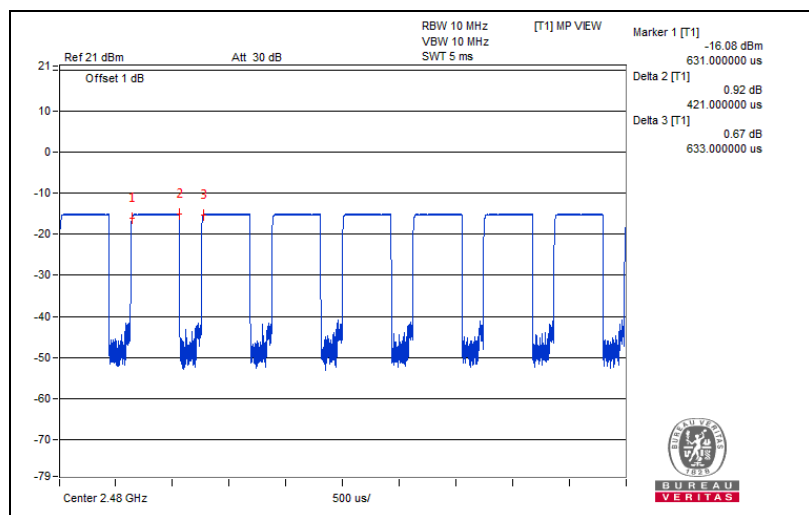
For BT-LE SAR Test Exclusion Thresholds

Frequency (GHz)	Max Avg. Power (dBm)	*Max Time Avg. Power (dBm)	Max Time Avg. Power (mW)	Min. test separation distance (mm)	SAR test exclusion calculation value ^(NOTE 1)	10-g SAR test exclusion thresholds	Result
2.402 ~ 2.480	1.98	0.21	1.05	5	0.328	7.5	Pass

- NOTE:** 1. The antenna type is chip antenna with 1.5dBi gain.
 2. Calculate SAR test exclusion thresholds from condition "1" formulas.
 3. *Time Avg. Power= Avg. Power+Duty factor

BT-LE Duty Cycle of Test Signal

Duty Cycle	Tx on (ms)	Tx total (ms)	Duty Factor (dB)
	0.421	0.663	-1.77
Duty Factor = $10 \cdot \log(\text{Tx on} / \text{Tx total})$			



4 Conclusion

Since Source-base time average power is below SAR test exclusion power thresholds, the SAR evaluation is not required.

--- END ---